

<b>Notice of References Cited</b>	Application/Control No. 10/582,440		Applicant(s)/Patent Under Reexamination CHO ET AL.	
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#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0032232 A1	10-2001	Zombek et al.	709/201
*	B	US-2003/0078061 A1	04-2003	Kim, Hoe-Won	455/466
*	C	US-2004/0250069 A1	12-2004	Kosamo, Rauno	713/168
*	D	US-7,310,307 B1	12-2007	Das et al.	370/229
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

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	N					
	O					
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	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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